Multilayer Ceramic Capacitors
Ultra-Small Series

RoHS Compliant

Description:

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used. 0201 MLCC is performed by high precision technology achieve high capacitance in unit size and ensure the stability and reliability of products.

Features:

- High capacitance in unit size
- High precision dimensional tolerances
- Suitable used in high-accuracy automatic mounting machine

Applications:

- Miniature microwave module.
- Portable equipments (ex. Mobile phone, PDA)
- High frequency circuits

External Dimensions:

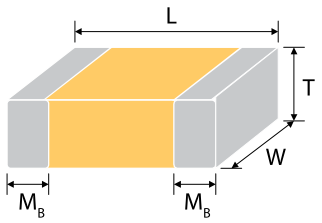

Fig. 1 The outline of MLCC

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		MB (mm)
0201 (0603)	0.6 ±0.03	0.3 ±0.03	0.3 ±0.03	L	0.15±0.05
	0.6 ±0.05[#1]	0.3 ±0.05[#1]	0.3 ±0.05 [#1]		

Reflow soldering only.
[#1] For 0201/Cap ≧0.68uF

General Electrical Data:

Size	0201		
Dielectric	**NP0**	**X7R**	**X5R**
Capacitance*	0.3pF to 100pF	100pF to 10nF	100pF to 1μF
Capacitance tolerance**	Cap≤5pF: B (±0.1pF), C (±0.25pF) 5pF<Cap<10pF: C (±0.25pF),D(±0.5pF) Cap≥10pF: F (±1%), G (±2%), J (±5%), K (±10%)	J (±5%), K (±10%), M (±20%)	J (±5%),K (±10%), M (±20%)
Rated voltage (WV DC)	16V, 25V, 50V	6.3V, 10V, 16V, 25V, 50V	6.3V, 10V, 16V, 25V, 50V
Tan δ / Q*	Cap<30pF, Q≥400+20C Cap≥30pF, Q≥1000	Note 1	
Insulation resistance at Ur	≥10GΩ	≥10GΩ or RxC≥500ΩxF whichever is less	
Operating temperature	-55 to +125°C	-55 to +85°C	
Capacitance change	±30ppm	±15%	
Termination	Ni/Sn (lead-free termination)		

* Measured at 30% ~ 70% related humidity.

NP0: Apply 1.0±0.2Vrms, 1.0MHz±10% at the condition of 25°C ambient temperature.

X7R, X5R: Apply 1.0±0.2Vrms, 1.0kHz±10%(0201/6.3V,Cap≥224 : 0.5±0.2Vrms, 1.0kHz±10%) at the condition of 25°C ambient temperature.

** Preconditioning for Class II MLCC: Perform a heat treatment at 150±10°C for 1 hour, then leave in ambient condition for 24±2 hours before measurement.

Note 1:

X7R/X5R

Rated vol.	D.F.	Exception of D.F.	
≥50V	≤3%	---	
25V	≤3.5%	≤5%	0201≥0.01uF
16V	≤3.5%	≤5%	0201≥0.01uF
10V	≤5%	≤10%	0201≥0.012uF
		≤15%	0201≥0.1uF
6.3V	≤10%	≤15%	0201≥0.1uF

Packaging Dimension And Quantity:

Size	Thickness (mm)/Symbol		Paper Tape	
			7" reel	**13" reel**
0201 (0603)	0.3 ±0.03	L	15,000	70,000
	0.3 ±0.05[#1]		15,000	-

#1 For 0201/Cap≧0.68uF

Multilayer Ceramic Capacitors
Ultra-Small Series

Capacitance Range:

Size		0201		
Dielectric		NP0		
Rated Voltage (V DC)		16	25	50
Capacitance	0.3pF (0R3)		L^	L^
	0.4pF (0R4)		L^	L^
	0.5pF (0R5)		L^	L^
	1.0pF (1R0)		L^	L^
	1.2pF (1R2)		L^	L^
	1.5pF (1R5)		L^	L^
	1.8pF (1R8)		L^	L^
	2.2pF (2R2)		L^	L^
	2.7pF (2R7)		L^	L^
	3.0pF (3R0)		L^	L^
	3.3pF (3R3)		L^	L^
	3.9pF (3R9)		L^	L^
	4.0pF(4R0)		L^	L^
	4.7pF (4R7)		L^	L^
	5.6pF (5R6)		L^	L^
	6.8pF (6R8)		L^	L^
	8.2pF (8R2)		L^	L^
	10pF (100)		L^	L^
	12pF (120)		L^	L^
	15pF (150)		L^	L^
	18pF (180)		L^	L^
	22pF (220)		L^	L^
	27pF (270)		L^	L^
	33pF (330)		L^	L^
	39pF (390)		L^	L^
	47pF (470)		L^	L^
	56pF (560)	L^	L^	L
	68pF (680)	L^	L^	L
	82pF (820)	L^	L^	L
	100pF (101)	L^	L^	L

Size		0201									
Dielectric		X7R					X5R				
Rated Voltage (V DC)		6.3	10	16	25	50	6.3	10	16	25	50
Capacitance	100pF (101)			L	L	L			L	L	L
	120pF (121)			L	L	L			L	L	L
	150pF (151)			L	L	L			L	L	L
	180pF (181)			L	L	L			L	L	L
	220pF (221)			L	L	L			L	L	L
	270pF (271)			L	L	L			L	L	L
	330pF (331)			L	L	L			L	L	L
	390pF (391)			L	L	L			L	L	L
	470pF (471)			L	L	L			L	L	L
	560pF (561)			L	L	L			L	L	L
	680pF (681)			L	L	L			L	L	L
	820pF (821)			L	L	L			L	L	L
	1,000pF (102)	L	L	L	L	L		L	L	L	L
	1,200pF (122)	L	L	L	L			L	L		
	1,500pF (152)	L	L	L	L			L	L		
	2,200pF (222)	L	L	L				L	L		
	3,300pF (332)	L	L	L				L	L		
	4,700pF (472)	L	L	L				L	L		
	6,800pF (682)	L	L					L			
	8,200pF (822)	L	L					L			
	0.010µF (103)	L	L	L			L	L			
	0.015µF (153)						L	L			
	0.022µF (223)						L	L			
	0.033µF (333)						L	L			
	0.047µF (473)						L	L			
	0.068µF (683)						L	L			
	0.082µF (823)						L	L			
	0.10µF (104)						L	L			
	0.22µF (224)						L				
	0.47µF (474)						L				
	1.0µF (105)						L				

1. The letter in cell is expressed the symbol of product thickness.
2. The letter in cell with “^” mark is expressed product with Ag/Ni/Sn terminations.

Reliability Test Conditions and Requirements:

<table>
<tr><th>No</th><th>Item</th><th>Test Condition</th><th>Requirements</th></tr>
<tr><td>1</td><td>Visual and Mechanical</td><td>-</td><td>No remarkable defect.
Dimensions to conform to individual specification sheet.</td></tr>
<tr><td>2</td><td>Capacitance</td><td rowspan="2">Class I: NP0
Cap≤1,000pF, 1.0±0.2Vrms, 1MHz±10%
Cap>1,000pF, 1.0±0.2Vrms, 1kHz±10%
Class II: X7R, X5R
1±0.2Vrms, 1kHz±10%
0.5±0.2Vrms, 1.0kHz±10% : 0201 ≥0.22 uF(6.3V)</td><td>Shall not exceed the limits given in the detailed spec.</td></tr>
<tr><td>3</td><td>Q/ D.F. (Dissipation Factor)</td><td>NP0: Cap≥30pF, Q≥1000; Cap<30pF, Q≥400+20C
X7R, X5R:
<table>
<tr><th>Rated Vol.</th><th>D.F.</th><th colspan="2">Exception of D.F.</th></tr>
<tr><td>≥50V</td><td>≤3%</td><td>---</td><td></td></tr>
<tr><td>25V</td><td>≤3.5%</td><td>≤5%</td><td>0201≥0.01uF</td></tr>
<tr><td>16V</td><td>≤3.5%</td><td>≤5%</td><td>0201≥0.01uF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≤5%</td><td>≤10%</td><td>0201≥0.012uF</td></tr>
<tr><td>≤15%</td><td>0201≥0.1uF</td></tr>
<tr><td>6.3V</td><td>≤10%</td><td>≤15%</td><td>0201≥0.1uF</td></tr>
</table></td></tr>
<tr><td>4a</td><td>Dielectric Strength</td><td>To apply voltage (≤100V) 250%.
Duration: 1 to 5 sec.
Charge and discharge current less than 50mA.</td><td>No evidence of damage or flash over during test.</td></tr>
<tr><td>5</td><td>Insulation Resistance</td><td>To apply rated voltage for max. 120 sec.</td><td>≥10GΩ or RxC≥500Ω-F whichever is smaller.
Class II
(X5R, X7R)
<table>
<tr><th>Related Voltage</th><th>Insulation Resistance</th></tr>
<tr><td>6.3V; 10V:0201≥47nF</td><td>≥100Ω-F</td></tr>
</table></td></tr>
<tr><td>6</td><td>Temperature Coefficient</td><td>With no electrical load.
<table>
<tr><th>T.C.</th><th>Operating Temperature</th></tr>
<tr><td>NP0 (C0G)</td><td>55~125°C at 25°C</td></tr>
<tr><td>X7R</td><td>-55~125°C at 25°C</td></tr>
<tr><td>X5R</td><td>-55~85°C at 25°C</td></tr>
</table></td><td>
<table>
<tr><th>T.C.</th><th>Capacitance Change</th></tr>
<tr><td>NP0 (C0G)</td><td>Within ±30ppm/°C</td></tr>
<tr><td>X7R</td><td>Within ±15%</td></tr>
<tr><td>X5R</td><td>Within ±15%</td></tr>
</table></td></tr>
<tr><td>7</td><td>Adhesive Strength of Termination</td><td>Pressurizing force: 2N
Test time: 10±1 sec.</td><td>No remarkable damage or removal of the terminations.</td></tr>
</table>

Reliability Test Conditions and Requirements:

<table>
<tr><th>No</th><th>Item</th><th>Test Condition</th><th>Requirements</th></tr>
<tr><td>8</td><td>Vibration
|Resistance</td><td>Vibration frequency: 10~55 Hz/min.
Total amplitude: 1.5mm
Test time: 6 hrs. (Two hrs each in three mutually perpendicular directions.)
Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>No remarkable damage.
Cap change and Q/D.F.: To meet initial spec.</td></tr>
<tr><td>9</td><td>Solderability</td><td>Solder temperature: 235±5°C</td><td>95% min. coverage of all metalized area.</td></tr>
<tr><td>10</td><td>Bending Test</td><td>The middle part of substrate shall be pressurized by means of the pressurizing rod at a rate of about 1 mm per second until the deflection becomes 1mm and then the pressure shall be maintained for 5±1 sec.
Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>No remarkable damage.
Cap change: NP0: within ±5.0% or ±0.5pF whichever is larger.
X7R, X5R: within ±12.5%
(This capacitance change means the change of capacitance under specified flexure of substrate from the capacitance measured before the test.)</td></tr>
<tr><td>11</td><td>Resistance to Soldering Heat</td><td>Solder temperature: 260±5°C
Dipping time: 10±1 sec
Preheating: 120 to 150°C for 1 minute before imme rse the capacitor in a eutectic solder.
Before initial measurement (Class II only): Perform 150+0/-10°C for 1 hr and then set for 24±2 hrs at r oom temp
Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>No remarkable damage.
Cap change:
NP0: within ±2.5% or ±0.25pF whichever is larger.
X7R, X5R: within ±7.5%
Q/D.F., I.R. and dielectric strength: To meet initial requirements.
25% max. leaching on each edge.</td></tr>
<tr><td>12</td><td>Temperature Cycle</td><td>Conduct the five cycles according to the temperatures and time.
<table>
<tr><th>Step</th><th>Temp. (°C)</th><th>Time (Min.)</th></tr>
<tr><td>1</td><td>Min. operating temp. +0/-3</td><td>30±3</td></tr>
<tr><td>2</td><td>Room temp.</td><td>2~3</td></tr>
<tr><td>3</td><td>Max. operating temp. +3/-0</td><td>30±3</td></tr>
<tr><td>4</td><td>Room temp.</td><td>2~3</td></tr>
</table>
Before initial measurement (Class II only): Perform 150+0/-10°C for 1 hour and then set for 24±2 hrs at room temp.
Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>No remarkable damage.
Cap change:
NP0: within ±2.5% or ±0.25pF whichever is larger.
X7R, X5R: within ±7.5%
Q/D.F., I.R. and dielectric strength: To meet initial requirements.</td></tr>
</table>

Reliability Test Conditions and Requirements:

<table>
<tr><th>No</th><th>Item</th><th>Test Condition</th><th>Requirements</th></tr>
<tr><td>13</td><td>Humidity
(Steady State)</td><td>Test temp.: 40±2°C
Humidity: 90~95% RH
Test time: 500+24/-0hrs.
Before initial measurement (Class II only): Perform 150+0/-10°C for 1 hr and then set for 24±2 hrs at r oom temp.
Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>No remarkable damage.
Cap change: NP0: within ±5.0% or ±0.5pF whichever is larger.
X7R, X5R: ≥10V, within ±12.5%,
10V^0.1μF, within ±25%;
6.3V, within ±25%
Y5V: ≥10V, within ±30%
6.3V, within +30/-40%
Q/D.F. value:
NP0: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275+2.5C Cap<10pF; Q≥200+10C
X7R, X5R:
<table>
<tr><th>Rated Vol.</th><th>D.F.</th><th colspan="2">Exception of D.F.</th></tr>
<tr><td>≥50V</td><td>≤6%</td><td>-</td><td></td></tr>
<tr><td>25V</td><td>≤5%</td><td>≤10%</td><td>0201≥0.01uF</td></tr>
<tr><td>16V</td><td>≤5%</td><td>≤15%</td><td>0201≥0.01uF</td></tr>
<tr><td rowspan="2">10V</td><td rowspan="2">≤7.5%</td><td>≤15%</td><td>0201≥0.012uF</td></tr>
<tr><td>≤20%</td><td>0201≥0.1uF</td></tr>
<tr><td>6.3V</td><td>≤15%</td><td>≤30%</td><td>0201≥0.1uF</td></tr>
</table>
I.R.: ≥10V, ≥1GΩ or RxC≥50Ω-F whichever is smaller.
6.3V; 10V:0201≥47nF, RxC≥10Ω-F</td></tr>
<tr><td>14</td><td>Humidity Load
(Damp Heat)</td><td>Test temp.: 40±2°C
Humidity: 90~95%RH
Test time: 500+24/-0 hrs.
To apply voltage: rated voltage.
Before initial measurement (Class II only): To apply test voltage for 1hr at 40°C and then set for 24±2 hrs a t room temp.
Measurement to be made after keeping at room temp. for 24±2 hrs.</td><td>No remarkable damage.
Cap change: NP0: within ±7.5% or ±0.75pF whichever is larger.
X7R, X5R: ≥10V, within ±12.5%,
10V≧0.1μF, within ±25%;
6.3V, within ±25%
Y5V: ≥10V, within ±30%
6.3V, within +30/-40%
Q/D.F. value:
NP0: Cap≥30pF, Q≥200; Cap<30pF, Q≥100+10/3C
X7R, X5R:
<table>
<tr><th>Rated Vol.</th><th>D.F.</th><th colspan="2">Exception of D.F.</th></tr>
<tr><td>≥50V</td><td>≤6%</td><td>-</td><td></td></tr>
<tr><td>25V</td><td>≤5%</td><td>≤10%</td><td>0201≥0.01uF</td></tr>
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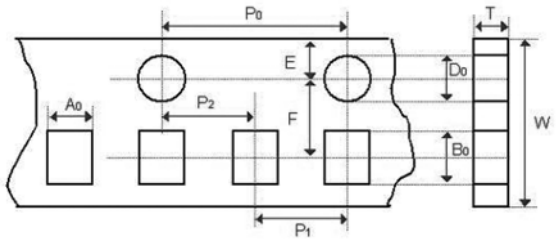
<tr><td>≤20%</td><td>0201≥0.1uF</td></tr>
<tr><td>6.3V</td><td>≤15%</td><td>≤30%</td><td>0201≥0.1uF</td></tr>
</table>
I.R.: ≥10V,500M or RxC≥25-F whichever is smaller.
6.3V; 10V:0201≥47nF, RxC≥5-F</td></tr>
</table>

Reliability Test Conditions and Requirements:

<table>
<tr><th>No</th><th>Item</th><th>Test Condition</th><th>Requirements</th></tr>
<tr><td>15</td><td>High Temperature Load (Endurance)</td><td>Test temp.:
NP0, X7R: 125±3°C
X5R,Y5V: 85±3°C
To apply voltage:
(1) Cap.≥0.1uF : 100% of rated voltage
(2) 6.3V: 150% of rated voltage.
(3) >6.3V: 200% of rated voltage.
Test time: 1000+24/-0 hrs.
Before initial measurement (Class II only): To apply test voltage for 1hr at test temp. and then set for 24±2 hrs at room temp.
Measurement to be made after keeping at room temp. for
24±2 hrs</td><td>No remarkable damage.
Cap change: NP0: within ±3.0% or ±0.3pF whichever is larger.
X7R, X5R: ≥10V, within ±12.5%,
10V≧0.1μF, within ±25%;
6.3V, within ±25%
Y5V: ≥10V, within ±30%
6.3V, within +30/-40%
Q/D.F. value:
NP0: Cap≥30pF, Q≥350; 10pF≤Cap<30pF, Q≥275+2.5C
Cap<10pF; Q≥200+10C
X7R, X5R:
<table>
<tr><th>Rated Vol.</th><th>D.F.</th><th colspan="2">Exception of D.F.</th></tr>
<tr><td>≥50V</td><td>≤6%</td><td>-</td><td></td></tr>
<tr><td>25V</td><td>≤5%</td><td>≤10%</td><td>0201≥0.01uF</td></tr>
<tr><td>16V</td><td>≤5%</td><td>≤15%</td><td>0201≥0.01uF</td></tr>
<tr><td>10V</td><td>≤7.5%</td><td>≤20%</td><td>0201≥0.1uF</td></tr>
<tr><td>6.3V</td><td>≤15%</td><td>≤30%</td><td>0201≥0.1uF</td></tr>
</table>
I.R.: ≥10V, ≥1G or RxC≥50-F whichever is smaller. 6.3V; 10V:0201≥47nF, RxC≥10-F</td></tr>
</table>

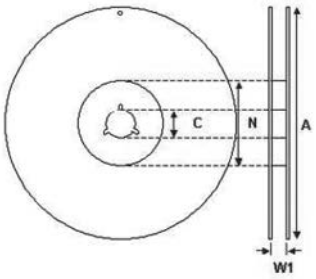
Appendixes

Tape & Reel Dimensions



The dimension of paper tape

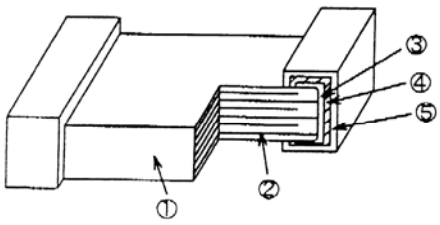
Size	0201
Thickness	L
A_0	0.38 ±0.05
B_0	0.68 ±0.05
T	0.42 ±0.05
K_0	-
W	8 ±0.1
P_0	4 ±0.1
$10xP_0$	40 ±0.1
P_1	2 ±0.05
P_2	2 ±0.05
D_0	1.55 ±0.05
D_1	-
E	1.75 ±0.05
F	3.5 ±0.05



The dimension of reel

Size	0201	
Reel size	7”	13”
C	13+0.5/-0.2	13+0.5/-0.2
W_1	8.4+1.5/-0	8.4+1.5/-0
A	178±0.1	330±1
N	60+1/-0	100±1

Constructions:



No.	Name		NP0	NP0, X7R, X5R
1	Ceramic material		$BaTiO_3$ based	
2	Inner electrode		AgPd alloy	Ni
3	Termination	Inner layer	Ag	Cu
4		Middle layer	Ni	
5		Outer layer	Sn (Matt)	

Storage and handling conditions

(1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions.

(2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

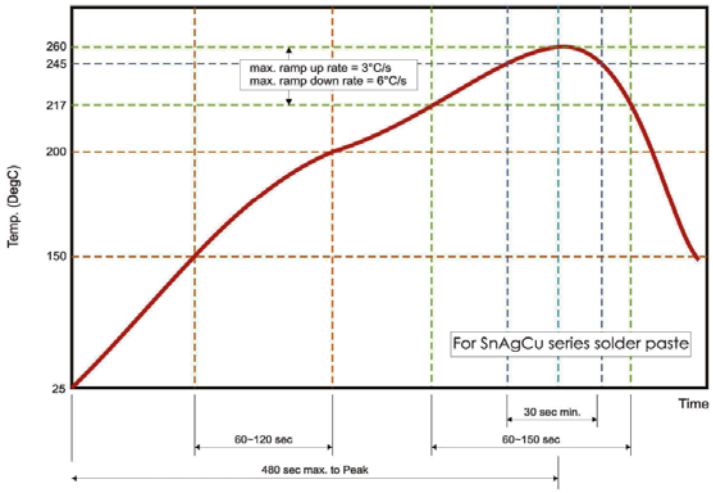
a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)

b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.

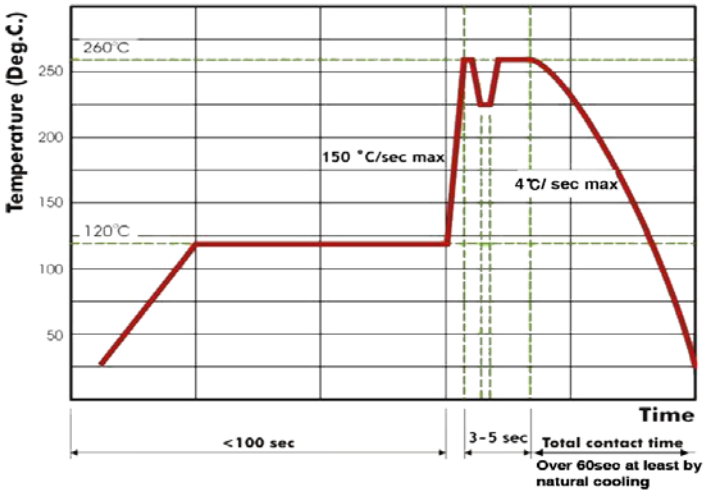
c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight,the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.

Recommended Soldering Conditions:

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N_2 within oven are recommended.



Recommended reflow soldering profile for SMT process with SnAgCu series solder paste.



Recommended wave soldering profile for SMT process with SnAgCu series solder.

Part Number Table

Description
Cap, MLCC, 100PF, 25V, NP0, 0201
Cap, MLCC, 100NF, 6.3V, X5R, 0201